

Notice of References Cited

Application/Control No.

10/584,351

Applicant(s)/Patent Under

Reexamination

ONISHI, HIDESHI

Examiner

John Freeman

Art Unit

1794

Page 1 of 1

U.S. PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A US-4,347,332 A	08-1982	Odorzynski et al.	524/169
*	B US-5,032,632 A	07-1991	Saxton, Ronald L.	524/139
*	C US-5,126,402 A	06-1992	Chou, Richard T.	525/58
*	D US-6,184,288 B1	02-2001	Ninomiya et al.	525/61
*	E US-6,565,938 B1	05-2003	Toyosumi et al.	428/36.6
*	F US-6,169,161	01-2001	Tachibana et al.	528/310
G	US-			
H	US-			
I	US-			
J	US-			
K	US-			
L	US-			
M	US-			

FOREIGN PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
N	WO 9618681 A1	06-1996	World Intellect	MIHARU et al.	C08L 29/04
O					
P					
Q					
R					
S					
T					

NON-PATENT DOCUMENTS

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
U	
V	
W	
X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a))
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.